Bridging the Scales:

Towards Parameter-Free Simulation-Aided OLED Design from Molecule to Device



Outline

- Introduction to Simbeyond
- Bumblebee: 3D kinetic Monte Carlo tool for OLEDs
- Simbeyond & SCM, towards a parameter-free multiscale toolchain from molecule to device
- Application of multiscale toolchain to TADF and hyperfluorescent materials and devices (Case studies with Cynora)





Simbeyond: accelerating OLED R&D

Commitment:

Reduce time to market and improve performance of OLED materials and applications by providing **predictive 3D simulation tools**

Markets:

OLEDs for displays, signage, and lighting; OPV; OFET

Users:

Chemical suppliers, device manufacturers, technology centers, and universities

Team expertise

What Simbeyond brings to OLED R&D teams

- Simulation software based on former **Philips OLED research and IP**
- Competences Simbeyond employees have **PhDs in:**
 - OLED Device Physics
 - Materials Science
 - Computational Chemistry
- Advisory board and team includes worldwide renowned experts in OLED R&D, scientific modeling and simulation
- Customers include some of the largest companies active in OLED
- Many universities using Bumblebee

Bumblebee: ultimate OLED device simulator

bumblebee™

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Predictions of device performance far beyond present tools

- Electrical characteristics
- Efficiency (roll-off)
- Color point and color stability
- Device degradation scenarios
- Lifetime prediction





Linking nanoscale material properties to macroscopic device performance



Simbeyond & SCM: Towards a parameter-free multiscale toolchain from molecule to device



Collaboration between Simbeyond & SCM:



Roles of partners in the toolchain

Calculating molecular level properties such as:

- IP/HOMO and EA/LUMO energies
- Exciton energies
- Transfer integrals

of each molecule in a realistic morphology

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Scaling of molecular level properties to device level and calculating device level properties such as:

- Charge transfer properties J(V)
- Excitonic events EQE
- Loss processes

in real 3D device dimensions

Multiscale toolchain: overall workflow



Current density [Am⁻²]

Demo time (SCM)



Connecting AMS and Bumblebee

Option 1

Using already generated hdf5 files for the layers of the OLED

Option 2

Using Simbeyond's Spiderweb environment for the automated workflow





Demo time (Simbeyond)

Energy scaling



- Each molecule's environment is taken into account with a polarizable QM/MM scheme using DRF method
- IP/EA energies: Delta-SCF method (framework of DFT)
- Exciton energies: TD-DFT with hybrid functionals
- The energies in the deposition boxes are scaled up to the device level, whilst keeping the mean and the sigma
 of the IP/EA and exciton energies identical

Device level simulations

Device Results





Available device simulation engines:

- 3D kinetic Monte Carlo
- 3D Master equation

Example capabilities of the multiscale toolchain:

- Predictive simulations for charge and excitonic processes
- Trend analysis for the *J*(*V*) and EQE for different devices
- Sensitivity analysis of various parameters



Case study with Cynora

Trend analysis on the *J*(*V*) and EQE of devices based on TADF and hyperfluorescent materials with different host-guest concentrations in the EML



TADF devices

EML concentrations:

- Device 1 = 9.3 mol% T; 90.7 mol% H
- Device 2 = 20.0 mol% T; 80.0 mol% H

Task of the case study:

Trend analysis on the *J*(*V*) and EQE of TADF devices with different host-guest concentrations

Approach:

Multiscale toolchain:

- HOMO, LUMO, and exciton energies
- Up to device performance



Molecular scale predictions - TADF

- **IP (HOMO) values**: fair agreement between predicted and experimental results
- EA (LUMO) values: differences between calculated and experimental results due to an inconsistent consideration of the exciton binding energy in conventional EA experiments
- **Excitonic energies**: fair agreement between predicted (2.59) and experimental (2.65) singlet energy of T molecule
- **Ordering** of the exciton energies as expected



Device level predictions – TADF



- Increasing T concentration in emission layer (EML) increases overall current density
- Fair prediction of *J*(*V*)



Device level predictions – TADF



- Excellent prediction of the EQE
- Main loss mechanisms: Non-radiative decay & singlet quenching, occurring mostly on T molecules
- Emission of the device is exclusively from T molecules



HF devices

EML concentrations:

- Device 1: 0.7 mol% F, 9.3 mol% T, 90 % mol H
- Device 2: 0.7 mol% F, 20.0 mol% T, 79.3 %mol H

Task of the case study:

Trend analysis of *J*(*V*) and EQE of HF devices with different host-guest concentrations

Approach:

Multiscale toolchain:

- HOMO, LUMO, and exciton energies
- Up to device performance





Molecular scale predictions – HF

2.0

Ó

20

40

60

- HOMO and LUMO values: similar conclusions as for the TADF stack. Ordering of the energy levels is consistent.
- **Excitonic energies**: fair agreement between predicted (2.57 eV) and experimental (2.45 eV) singlet energy of F molecule.
- **Ordering** of the exciton energies as expected



80

Distance from anode [nm]

100

120

140

Device level predictions - HF



- Increasing T concentration in the emission layer (EML) increases the overall current density
- Fair prediction of the *J*(*V*)



Device level predictions - HF



- The experimental trend in the EQE is very well predicted
- Non-radiative decay and triplet quenching are the main loss mechanism that occur mostly on the F molecules
- The emission of the device is exclusively from the F molecules.

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* 25 % outcoupling efficiency is assumed ** It is assumed that the mobility of F molecule is lower than other molecules in the device

6.0



Demo time (Simbeyond)

Summary and conclusions

- Our multiscale toolchain developed with SCM allows to explore the device level properties of OLEDs without the need of experimental input parameters
- Our toolchain is now operational and validated for electronic and excitonic trend predictions
- It is also possible to extend our toolchain with the other features of Bumblebee such as device degradation scenarios and lifetime prediction of the OLEDs



Contact details



engin.torun@simbeyond.com

Eindhoven, the Netherlands

simbeyond.com



Backup slides



Overview of simulation methods

	1D Drift Diffusion	3D Master Equations	3D Kinetic Monte Carlo
Overall Accuracy	_	+	++
Simulation speed	++	+	~
Charge transport	~	+	++
Excitonic processes	~	+	++
Complex device structures		+	++
Input parameters/ Simulation workflow	~	++	++
Predictiveness	~	+	++

Overview of collaboration possibilities

Simbeyond's product and service portfolio

Software & support



Bumblebee Licenses & Services (1+ months)

- Bumblebee License Units
- Additional modules
- Technical support
- Local support

Knowledge & Training



Masterclass Interactive workshop Training program

- Bumblebee training & results
- Direct hands-on support
- Lectures and interactive Q&A
- Bumblebee License Units
- Additional modules

Consultancy & Projects



On-demand expertise Project in cooperative mode Project outsourced to Simbeyond

- OLED material and device experts
- Direct hands-on support
- Local support & consultancy
- Bumblebee License Units
- Additional modules



Molecular scale predictions





Device level predictions – TADF



Morphology scaling

Nearest-neighbor (NN) distance **Deposition box Scaled box** distribution comparison Scaled box ab inito box Nearest-neighbor dist. distri. O 20 15 (mn) Z (nm) Z (nm) **Stochastic** 5 ₀ scaling* 20 Zam 1,0,6 0 x (10) 15 x²(nm) 0 0.5 1 0 0 20 Distance (nm) 4.95 × 4.29 × 5.37 nm³ 20 × 20 × 20 nm³ 184 molecules, 12841 molecules, Good agreement in NN distance $n = 1.61 \text{ molecule/nm}^3$ $n = 1.60 \text{ molecule/nm}^3$ distribution min. NN dist = 0.59 nm min. NN dist = 0.62 nm

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Opportunity: simulation-assisted approach

Our 3D Kinetic Monte Carlo approach enables to go beyond the conventional trial-and error approach:

